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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	310
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	100
Number of Gates	2500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	132-BCQFP with Tie Bar
Supplier Device Package	132-CQFP (63.5x63.5)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1425a-1cq132b

1 – ACT 3 Family Overview

General Description

Microsemi's ACT 3 Accelerator Series of FPGAs offers the industry's fastest high-capacity programmable logic device. ACT 3 FPGAs offer a high performance, PCI compliant programmable solution capable of 186 MHz on-chip performance and 9.0 nanosecond clock-to-output (–1 speed grade), with capacities spanning from 1,500 to 10,000 gate array equivalent gates.

The ACT 3 family builds on the proven two-module architecture consisting of combinatorial and sequential logic modules used in Microsemi's 3200DX and 1200XL families. In addition, the ACT 3 I/O modules contain registers which deliver 9.0 nanosecond clock-to-out times (–1 speed grade). The devices contain four clock distribution networks, including dedicated array and I/O clocks, supporting very fast synchronous and asynchronous designs. In addition, routed clocks can be used to drive high fanout signals such as flip-flop resets and output.

The ACT 3 family is supported by Microsemi's Designer Series Development System which offers automatic placement and routing (with automatic or fixed pin assignments), static timing analysis, user programming, and debug and diagnostic probe capabilities.

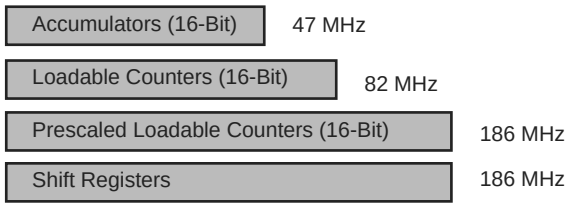
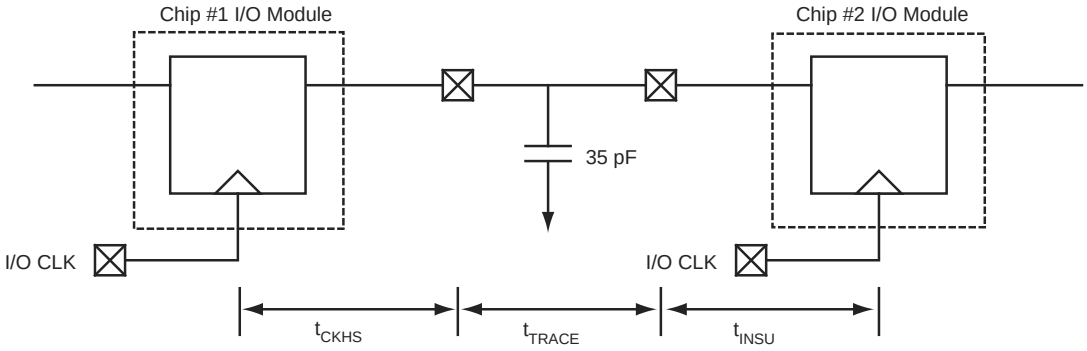


Figure 1-1 • **Predictable Performance (worst-case commercial, –1 speed grade)**

System Performance Model



2 – Detailed Specifications

This section of the datasheet is meant to familiarize the user with the architecture of the ACT 3 family of FPGA devices. A generic description of the family will be presented first, followed by a detailed description of the logic blocks, the routing structure, the antifuses, and the special function circuits. The on-chip circuitry required to program the devices is not covered.

Topology

The ACT 3 family architecture is composed of six key elements: Logic modules, I/O modules, I/O Pad Drivers, Routing Tracks, Clock Networks, and Programming and Test Circuits. The basic structure is similar for all devices in the family, differing only in the number of rows, columns, and I/Os. The array itself consists of alternating rows of modules and channels. The logic modules and channels are in the center of the array; the I/O modules are located along the array periphery. A simplified floor plan is depicted in Figure 2-1.

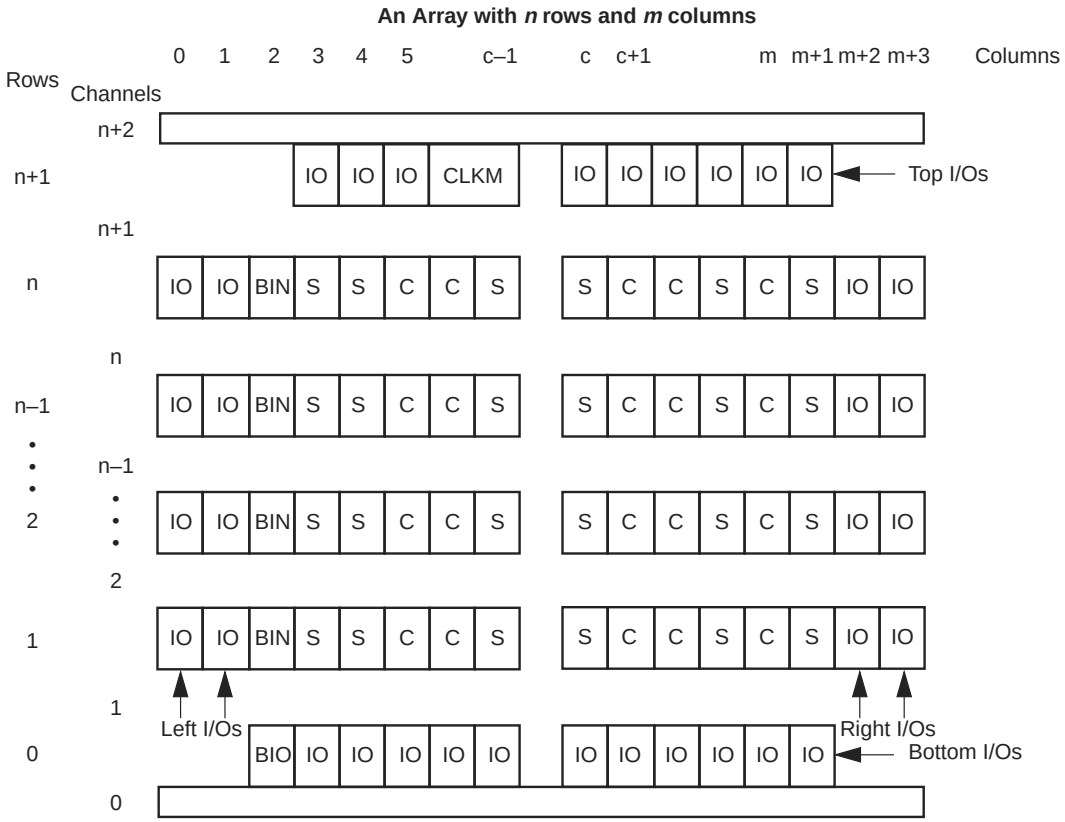


Figure 2-1 • **Generalized Floor Plan of ACT 3 Device**

The I/O module output Y is used to bring Pad signals into the array or to feed the output register back into the array. This allows the output register to be used in high-speed state machine applications. Side I/O modules have a dedicated output segment for Y extending into the routing channels above and below (similar to logic modules). Top/Bottom I/O modules have no dedicated output segment. Signals coming into the chip from the top or bottom are routed using F-fuses and LVTs (F-fuses and LVTs are explained in detail in the routing section).

I/O Pad Drivers

All pad drivers are capable of being tristate. Each buffer connects to an associated I/O module with four signals: OE (Output Enable), IE (Input Enable), DataOut, and DataIn. Certain special signals used only during programming and test also connect to the pad drivers: OUTEN (global output enable), INEN (global input enable), and SLEW (individual slew selection). See Figure 2-5.

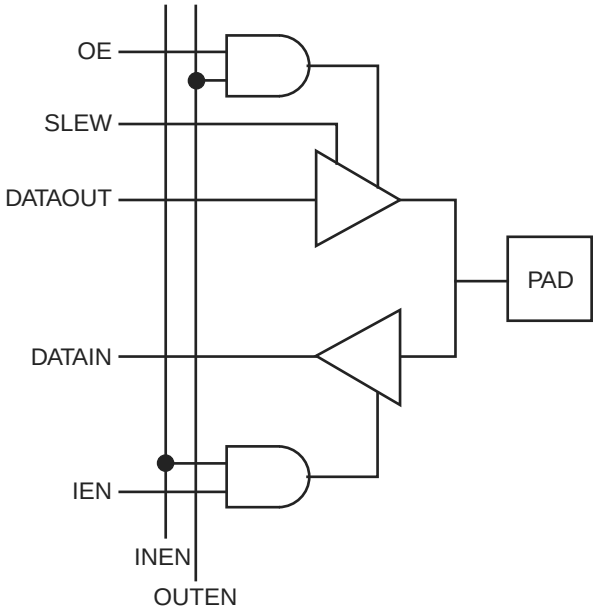


Figure 2-5 • **Function Diagram for I/O Pad Driver**

Special I/Os

The special I/Os are of two types: temporary and permanent. Temporary special I/Os are used during programming and testing. They function as normal I/Os when the MODE pin is inactive. Permanent special I/Os are user programmed as either normal I/Os or special I/Os. Their function does not change once the device has been programmed. The permanent special I/Os consist of the array clock input buffers (CLKA and CLKB), the hard-wired array clock input buffer (HCLK), the hard-wired I/O clock input buffer (IOCLK), and the hard-wired I/O register preset/clear input buffer (IOPCL). Their function is determined by the I/O macros selected.

Clock Networks

The ACT 3 architecture contains four clock networks: two high-performance dedicated clock networks and two general purpose routed networks. The high-performance networks function up to 200 MHz, while the general purpose routed networks function up to 150 MHz.

3.3 V Operating Conditions

Table 2-5 • **Absolute Maximum Ratings[1], Free Air Temperature Range**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current[2]	±20	mA
T_{STG}	Storage temperature	–65 to +150	°C

Notes:

1. *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.*
2. *Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.*

Table 2-6 • **Recommended Operating Conditions**

Parameter	Commercial	Units
Temperature range*	0 to +70	°C
Power supply tolerance	3.0 to 3.6	V

*Note: *Ambient temperature (T_A) is used for commercial.*

Table 2-7 • **Electrical Specifications**

Parameter		Commercial		Units
		Min.	Max.	
VOH[1]	IOH = –4 mA	2.15	–	V
	IOH = –3.2 mA	2.4		V
VOL[1]	IOL = 6 mA		0.4	V
VIL		–0.3	0.8	V
VIH		2.0	VCC + 0.3	V
Input transition time t_R, t_F[2]	VI = VCC or GND	–10	+10	µA
C_{IO} I/O Capacitance[2,3]			10	pF
Standby current, ICC[4] (typical = 0.3 mA)			0.75	mA
Leakage current[5]		–10	10	µA

1. *Only one output tested at a time. VCC = minimum.*
2. *Not tested; for information only.*
3. *Includes worst-case 84-pin PLCC package capacitance. VOUT = 0 V, f - 1 MHz.*
4. *Typical standby current = 0.3 mA. All outputs unloaded. All inputs = VCC or GND.*
5. *VO, VIN = VCC or GND*

Package Thermal Characteristics

The device junction to case thermal characteristic is θjc, and the junction to ambient air characteristic is θja. The thermal characteristics for θja are shown with two different air flow rates.

Maximum junction temperature is 150°C.

A sample calculation of the absolute maximum power dissipation allowed for a CPGA 175-pin package at commercial temperature and still air is as follows:

$$\frac{\text{Max. junction temp. (°C)} - \text{Max. ambient temp. (°C)}}{\theta_{ja}\text{°C/W}} = \frac{150\text{°C} - 70\text{°C}}{25\text{°C/W}} = 3.2\text{ W}$$

EQ 2

Table 2-8 • **Package Thermal Characteristics**

Package Type*	**Pin Count**	θ_{jc}	θ_{ja} **Still Air**	θ_{ja} **300 ft./min.**	**Units**
Ceramic Pin Grid Array	100	20	35	17	°C/W
	133	20	30	15	°C/W
	175	20	25	14	°C/W
	207	20	22	13	°C/W
	257	20	15	8	°C/W
Ceramic Quad Flatpack	132	13	55	30	°C/W
	196	13	36	24	°C/W
	256	13	30	18	°C/W
Plastic Quad Flatpack	100	13	51	40	°C/W
	160	10	33	26	°C/W
	208	10	33	26	°C/W
Very Thin Quad Flatpack	100	12	43	35	°C/W
Thin Quad Flatpack	176	11	32	25	°C/W
Power Quad Flatpack	208	0.4	17	13	°C/W
Plastic Leaded Chip Carrier	84	12	37	28	°C/W
Plastic Ball Grid Array	225	10	25	19	°C/W
	313	10	23	17	°C/W

Note: Maximum power dissipation in still air:
PQ160 = 2.4 W
PQ208 = 2.4 W
PQ100 = 1.6 W
VQ100 = 1.9 W
TQ176 = 2.5 W
PL84 = 2.2 W
RQ208 = 4.7 W
BG225 = 3.2 W
BG313 = 3.5 W

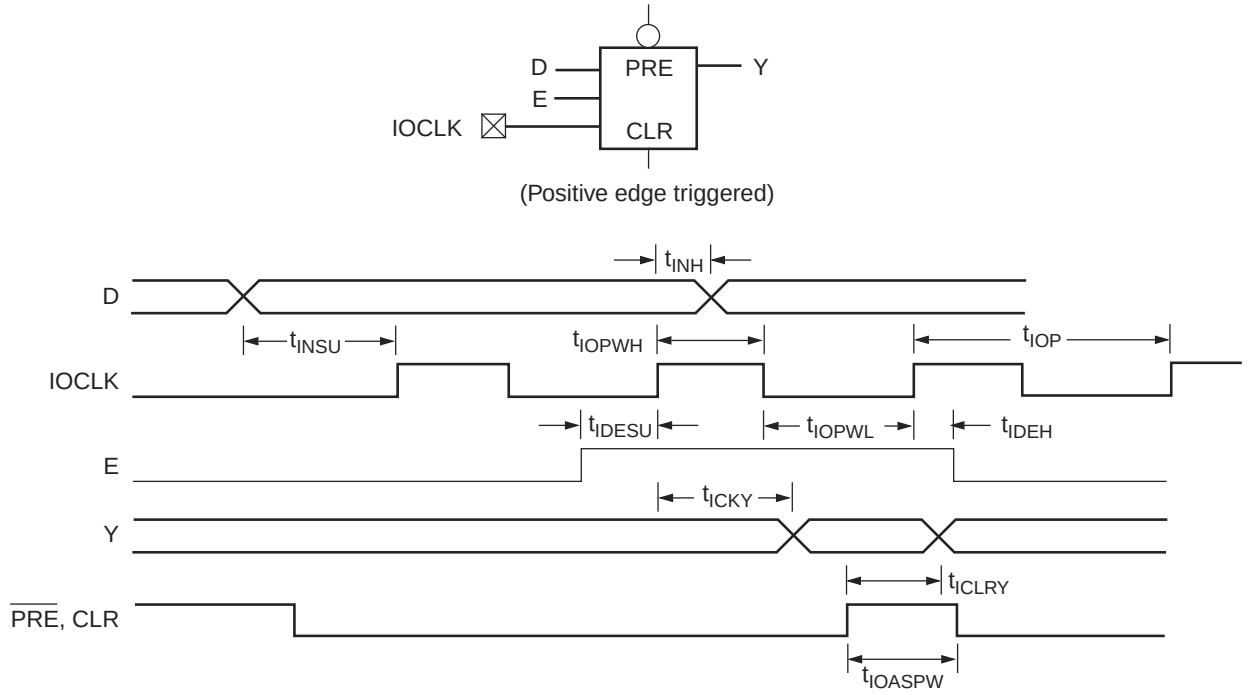


Figure 2-16 • **I/O Module: Sequential Input Timing Characteristics**

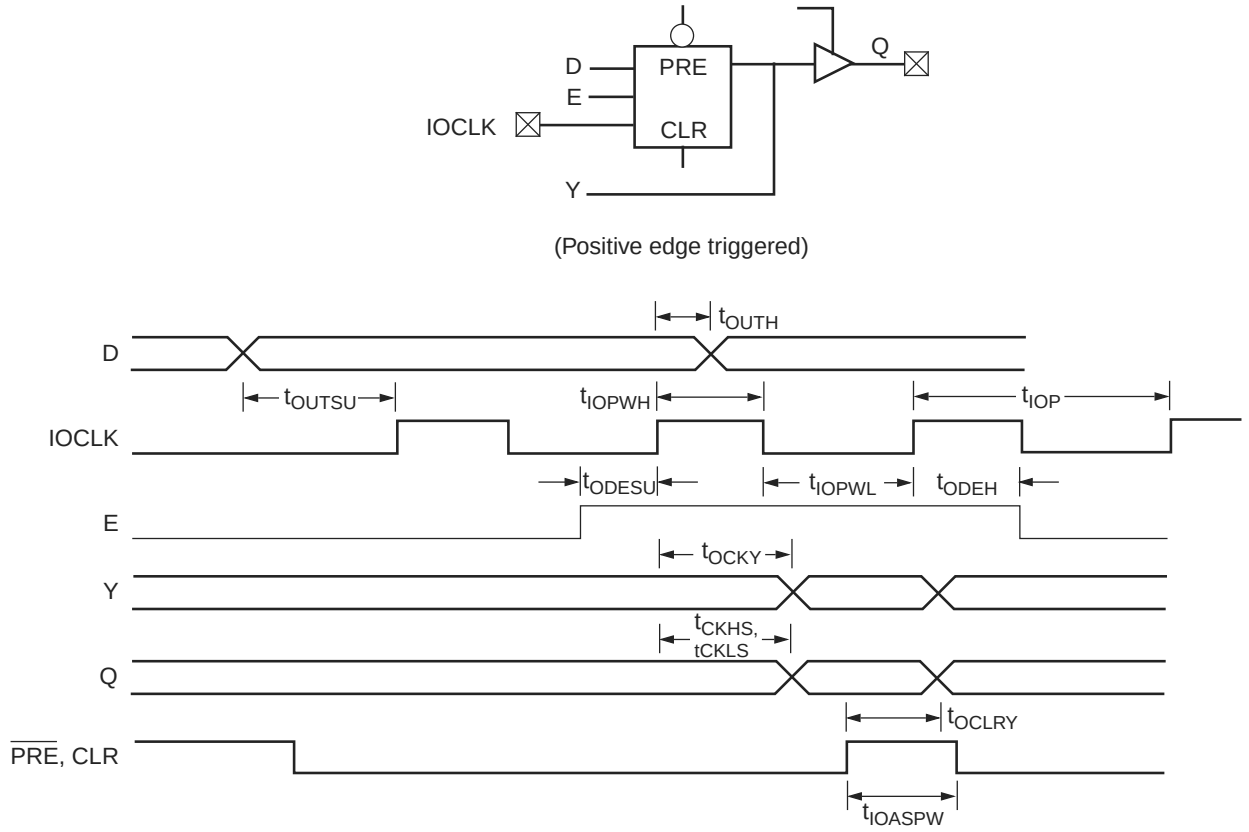


Figure 2-17 • **I/O Module: Sequential Output Timing Characteristics**

Tightest Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer lengths of routing track. The ACT 3 family delivers the tightest fanout delay distribution of any FPGA. This tight distribution is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented PLICE antifuse offers a very low resistive/capacitive interconnect. The ACT 3 family's antifuses, fabricated in 0.8 micron m lithography, offer nominal levels of 200Ω resistance and 6 femtofarad (fF) capacitance per antifuse. The ACT 3 fanout distribution is also tighter than alternative devices due to the low number of antifuses required per interconnect path. The ACT 3 family's proprietary architecture limits the number of antifuses per path to only four, with 90% of interconnects using only two antifuses.

The ACT 3 family's tight fanout delay distribution offers an FPGA design environment in which fanout can be traded for the increased performance of reduced logic level designs. This also simplifies performance estimates when designing with ACT 3 devices.

***Table 2-14* • Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions**

Speed Grade	FO = 1	FO = 2	FO = 3	FO = 4	FO = 8
ACT 3 –3	2.9	3.2	3.4	3.7	4.8
ACT 3 –2	3.3	3.7	3.9	4.2	5.5
ACT 3 –1	3.7	4.2	4.4	4.8	6.2
ACT 3 STD	4.3	4.8	5.1	5.5	7.2

Notes:

1. *Obtained by added $t_{RD(x=FO)}$ to t_{PD} from the Logic Module Timing Characteristics Tables found in this datasheet.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

Timing Characteristics

Timing characteristics for ACT 3 devices fall into three categories: family dependent, device dependent, and design dependent. The input and output buffer characteristics are common to all ACT 3 family members. Internal routing delays are device dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design is complete. Delay values may then be determined by using the ALS Timer utility or performing simulation with post-layout delays.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most time-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6% of the nets in a design may be designated as critical, while 90% of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections. This increases capacitance and resistance, result ng in longer net delays for macros connected to long tracks. Typically up to 6% of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 14 ns delay. This additional delay is represented statistically in higher fanout (FO = 8) routing delays in the datasheet specifications section.

A1440A, A14V40A Timing Characteristics (continued)

Table 2-28 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing[1]		–3 Speed[2]		–2 Speed[2]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		8.5		8.5		9.5		11.0		14.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.1		11.8		14.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A1460A, A14V60A Timing Characteristics

Table 2-30 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C[1]

Logic Module Propagation Delays[2]		–3 Speed[3]		–2 Speed [3]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t_{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t_{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays[4]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t_{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t_{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t_{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t_A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f_{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. *VCC = 3.0 V for 3.3 V specifications.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn}$ or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
4. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A14100A, A14V100A Timing Characteristics

Table 2-34 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C[1]

Logic Module Propagation Delays[2]		–3 Speed[3]		–2 Speed [3]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t_{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t_{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays[4]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t_{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t_{SUD}	Latch Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t_{HD}	Latch Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t_{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t_{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t_A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f_{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. *VCC = 3.0 V for 3.3 V specifications.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn}$ or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
4. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A14100A, A14V100A Timing Characteristics (continued)

Table 2-36 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing[1]		–3 Speed[2]		–2 Speed[2]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.5		9.5		10.5		12.0		15.6	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.0		12.0		15.6	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.4		13.8		17.9	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

*Notes: **

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A14100A, A14V100A Timing Characteristics (continued)

Table 2-37 • **A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

Dedicated (hardwired) I/O Clock Network		–3 Speed[1]		–2 Speed[1]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{IOCKH}	Input Low to High (pad to I/O module input)		2.3		2.6		3.0		3.5		4.5	ns
t_{IOPWH}	Minimum Pulse Width High	2.4		3.3		3.8		4.8		6.5		ns
t_{IPOWL}	Minimum Pulse Width Low	2.4		3.3		3.8		4.8		6.5		ns
t_{IOSAPW}	Minimum Asynchronous Pulse Width	2.4		3.3		3.8		4.8		6.5		ns
t_{IOCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		0.6	ns
t_{IOP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f_{IOMAX}	Maximum Frequency		200		150		125		100		75	MHz
Dedicated (hardwired) Array Clock												
t_{HCKH}	Input Low to High (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t_{HCKL}	Input High to Low (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t_{HPWH}	Minimum Pulse Width High	2.4		3.3		3.8		4.8		6.5		ns
t_{HPWL}	Minimum Pulse Width Low	2.4		3.3		3.8		4.8		6.5		ns
t_{HCKSW}	Delta High to Low, Low Slew		0.6		0.6		0.7		0.8		0.6	ns
t_{HP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f_{HMAX}	Maximum Frequency		200		150		125		100		75	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t_{RCKL}	Input High to Low (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t_{RPWH}	Min. Pulse Width High (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t_{RPWL}	Min. Pulse Width Low (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t_{RCKSW}	Maximum Skew (FO = 128)		1.2		1.4		1.6		1.8		1.8	ns
t_{RP}	Minimum Period (FO = 64)	8.3		9.3		11.1		12.5		16.7		ns
f_{RMAX}	Maximum Frequency (FO = 64)		120		105		90		80		60	MHz
Clock-to-Clock Skews												
$t_{IOHCKSW}$	I/O Clock to H-Clock Skew	0.0	2.6	0.0	2.7	0.0	2.9	0.0	3.0	0.0	3.0	ns
$t_{IORCKSW}$	I/O Clock to R-Clock Skew (FO = 64) (FO = 350)	0.0 0.0	1.7 5.0	0.0 0.0	1.7 5.0	0.0 0.0	1.7 5.0	0.0 0.0	1.7 5.0	0.0 0.0	5.0 5.0	ns
t_{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 350)	0.0 0.0	1.3 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	ns

*Notes: **

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Delays based on 35 pF loading.*

SDO **Serial Data Output (Output)**

Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

DCLK **Diagnostic Clock (Input)**

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

VCC **5 V Supply Voltage**

HIGH supply voltage.

CQ196	
Pin Number	**A1460 Function**
1	GND
2	SDI, I/O
11	MODE
12	VCC
13	GND
37	GND
38	VCC
39	VCC
51	GND
52	GND
59	VCC
64	GND
77	HCLK, I/O
79	PRB, I/O
86	GND
94	VCC
98	GND
99	SDO
100	IOPCL, I/O

CQ196	
Pin Number	**A1460 Function**
101	GND
110	VCC
111	VCC
112	GND
137	VCC
138	GND
139	GND
140	VCC
148	IOCLK, I/O
149	GND
155	VCC
162	GND
172	CLKA, I/O
173	CLKB, I/O
174	PRA, I/O
183	GND
189	VCC
193	GND
196	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

BG225	
A1460 Function	**Location**
CLKA or I/O	C8
CLKB or I/O	B8
DCLK or I/O	B2
GND	A1, A15, D15, F8, G7, G8, G9, H6, H7, H8, H9, H10, J7, J8, J9, K8, P2, R15
HCLK or I/O	P9
IOCLK or I/O	B14
IOPCL or I/O	P14
MODE	D1
NC	A11, B5, B7, D8, D12, F6, F11, H1, H12, H14, K11, L1, L13, N8, P5, R1, R8, R11, R14
PRA or I/O	A7
PRB or I/O	L7
SDI or I/O	D4
SDO	N13
VCC	A8, B12, D5, D14, E3, E8, E13, H2, H3, H11, H15, K4, L2, L12, M8, M15, P4, P8, R13

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The BG225 package has been discontinued.

PG100	
A1415 Function	**Location**
CLKA or I/O	C7
CLKB or I/O	D6
DCLK or I/O	C4
GND	C3, C6, C9, E9, F3, F9, J3, J6, J8, J9
HCLK or I/O	H6
IOCLK or I/O	C10
IOPCL or I/O	K9
MODE	C2
PRA or I/O	A6
PRB or I/O	L3
SDI or I/O	B3
SDO	L9
VCC	B6, B10, E11, F2, F10, G2, K2, K6, K10

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG100 package has been discontinued.

PG133	
A1425 Function	**Location**
CLKA or I/O	D7
CLKB or I/O	B6
DCLK or I/O	D4
GND	A2, C3, C7, C11, C12, F10, G3, G11, L3, L7, L11, M3, N12
HCLK or I/O	K7
IOCLK or I/O	C10
IOPCL or I/O	L10
MODE	E3
NC	A1, A7, A13, G1, G13, N1, N7, N13
PRA or I/O	A6
PRB or I/O	L6
SDI or I/O	C2
SDO	M11
VCC	B2, B7, B12, E11, G2, G12, J2, J12, M2, M7, M12

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG133 package has been discontinued.

PG257	
A14100 Function	**Location**
CLKA or I/O	L4
CLKB or I/O	L5
DCLK or I/O	E4
GND	B16, C4, D4, D10, D16, E11, J5, K4, K16, L15, R4, T4, T10, T16, T17, X7
HCLK or I/O	J16
IOCLK or I/O	T5
IOPCL or I/O	R16
MODE	A5
NC	E5
PRA or I/O	J1
PRB or I/O	J17
SDI or I/O	B4
SDO	R17
VCC	C3, C10, C13, C17, K3, K17, V3, V7, V10, V17, X14

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

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